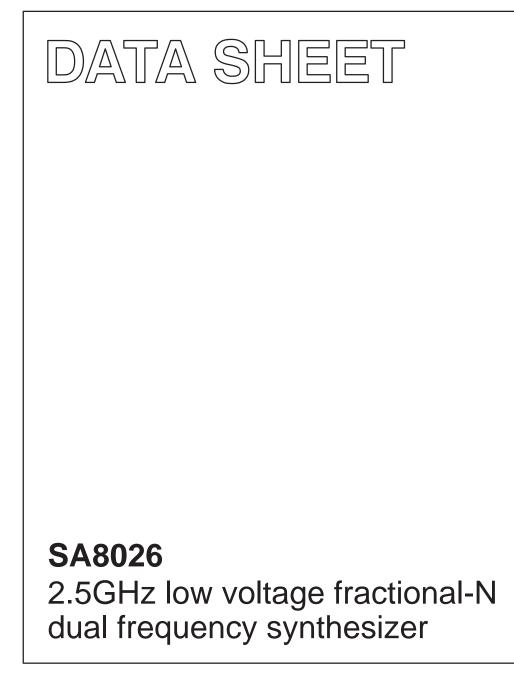
## INTEGRATED CIRCUITS



Product specification Supersedes data of 1999 Apr 16 1999 Nov 04



Philips Semiconductors

SA8026

#### **GENERAL DESCRIPTION**

The SA8026 BICMOS device integrates programmable dividers, charge pumps and a phase comparator to implement a phase-locked loop. The device is designed to operate from 3 NiCd cells, in pocket phones, with low current and nominal 3 V supplies.

The synthesizer operates at VCO input frequencies up to 2.5 GHz. The synthesizer has fully programmable main, auxiliary and reference dividers. All divider ratios are supplied via a 3-wire serial programming bus.

Separate power and ground pins are provided to the analog and digital circuits. The ground leads should be externally short-circuited to prevent large currents flowing across the die and thus causing damage.  $V_{DDCP}$  must be greater than or equal to  $V_{DD}$ .

The charge pump current (gain) is set by an external resistance at  $R_{SET}$  pin. Passive loop filters could be used; the charge pump operates within a wide voltage compliance range to provide a wider tuning range.

#### **FEATURES**

- Low phase noise
- Low power
- Fully programmable main and auxiliary dividers
- Normal & Integral charge pumps outputs
- Fast Locking Adaptive mode design
- Internal fractional spurious compensation
- Hardware and software power down
- Split supply for V<sub>DD</sub> and V<sub>DDCP</sub>

#### QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT	
V <sub>DD</sub>	Supply voltage		2.7	-	5.5	V	
V <sub>DDCP</sub>	Analog supply voltage	$V_{DDCP} \ge V_{DD}$	2.7	-	5.5	V	
I <sub>DDCP</sub> +I <sub>DD</sub>	Total supply current	Main and Aux. on	-	10	12	mA	
I <sub>DDCP</sub> +I <sub>DD</sub>	Total supply current in power-down mode		-	1	-	μΑ	
f <sub>VCO</sub>	Input frequency		350	-	2500	MHz	
f <sub>AUX</sub>	Input frequency		20	-	550	MHz	
f <sub>REF</sub>	Crystal reference input frequency		5	-	40	MHz	
f <sub>PC</sub>	Maximum phase comparator frequency		-		4	MHz	
T <sub>amb</sub>	Operating ambient temperature		-40	-	+85	°C	

#### **ORDERING INFORMATION**

	PACKAGE	PACKAGE								
ITPE NUMBER	NAME	VERSION								
SA8026DH	TSSOP20	Plastic thin shrink small outline package; 20 leads; body width 4.4 mm	SOT360-1							

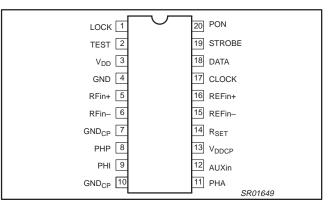


Figure 1. Pin Configuration

#### **APPLICATIONS**

- 350 to 2500 MHz wireless equipment
- Cellular phones (all standards)
- WLAN
- Portable battery-powered radio equipment.

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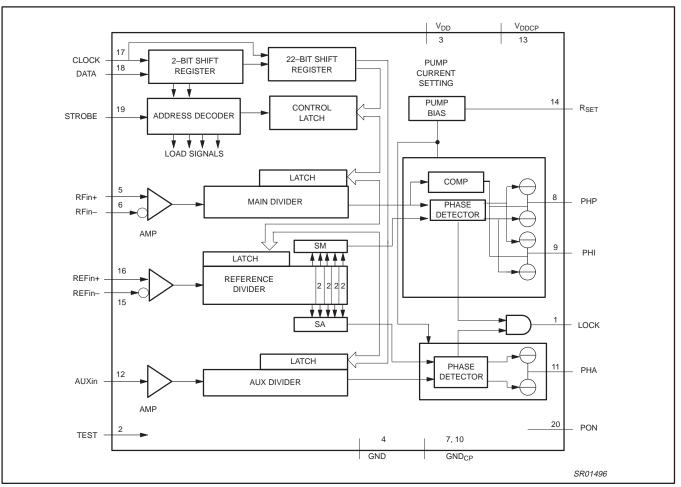


Figure 2. Block Diagram

#### PINNING

SYMBOL	PIN	DESCRIPTION
LOCK	1	Lock detect output
TEST	2	Test (should be either grounded or connected to $V_{DD}$ )
V <sub>DD</sub>	3	Digital supply
GND	4	Digital ground
RFin+	5	RF input to main divider
RFin-	6	RF input to main divider
GND <sub>CP</sub>	7	Charge pump ground
PHP	8	Main normal charge pump
PHI	9	Main integral charge pump
GND <sub>CP</sub>	10	Charge pump ground

SYMBOL	PIN	DESCRIPTION
PHA	11	Auxiliary charge pump output
AUXin	12	Input to auxiliary divider
V <sub>DDCP</sub>	13	Charge pump supply voltage
R <sub>SET</sub> 14 External resistor from this pin to sets the charge pump current		External resistor from this pin to ground sets the charge pump current
REFin-	15	Reference input
REFin+	16	Reference input
CLOCK	17	Programming bus clock input
DATA	18	Programming bus data input
STROBE	19	Programming bus enable input
PON	20	Power down control

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#### Limiting values

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
V <sub>DD</sub>	Digital supply voltage	-0.3	+5.5	V
V <sub>DDCP</sub>	Analog supply voltage	-0.3	+5.5	V
$\Delta V_{DDCP} - V_{DD}$	Difference in voltage between V_DDCP and V_DD (V_DDCP $\ge$ V_DD)	-0.3	+2.8	V
V <sub>n</sub>	Voltage at pins 1, 2, 5, 6, 12, 15 to 20	-0.3	V <sub>DD</sub> + 0.3	V
V <sub>n</sub>	Voltage at pin 8, 9, 11	-0.3	V <sub>DDCP</sub> + 0.3	V
$\Delta V_{GND}$	Difference in voltage between $GND_{CP}$ and $GND$ (these pins should be connected together)	-0.3	+0.3	V
T <sub>stg</sub>	Storage temperature	-55	+125	°C
T <sub>amb</sub>	Operating ambient temperature	-40	+85	°C
Т <sub>j</sub>	Maximum junction temperature		150	°C

#### Handling

Inputs and outputs are protected against electrostatic discharge in normal handling. However, to be totally safe, it is desirable to take normal precautions appropriate to handling MOS devices.

#### **Thermal characteristics**

SYMBOL	PARAMETER	VALUE	UNIT
R <sub>th j–a</sub>	Thermal resistance from junction to ambient in free air	135	K/W

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### **CHARACTERISTICS**

 $V_{DDCP}$  =  $V_{DD}$  = +3.0V,  $T_{amb}$  = +25°C; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Supply; pir	is 3, 13	•	•			
V <sub>DD</sub>	Digital supply voltage		2.7	-	5.5	V
V <sub>DDCP</sub>	Analog supply voltage	$V_{DDCP} \ge V_{DD}$	2.7	-	5.5	V
I <sub>DDTotal</sub>	Synthesizer operational total supply current	V <sub>DD</sub> = +3.0V (with main and aux on)	-	10	12	mA
I <sub>Standby</sub>	Total supply current in power-down mode	logic levels 0 or VDD	-	1	-	μΑ
RFin main	divider input; pins 5, 6	-				
f <sub>VCO</sub>	VCO input frequency		350	-	2500	MHz
V <sub>RFin(rms)</sub>	AC-coupled input signal level	$\begin{array}{l} {\sf R}_{in} \mbox{ (external)} = {\sf R}_{s} = 50 \Omega; \\ \mbox{single-ended drive;} \\ \mbox{max. limit is indicative} \\ @ 500 \mbox{ to } 2500 \mbox{ MHz} \end{array}$	-18	-	0	dBm
Z <sub>IRFin</sub>	Input impedance (real part)	$f_{VCO} = 2.4 \text{ GHz}$	-	300	-	Ω
C <sub>IRFin</sub>	Typical pin input capacitance	f <sub>VCO</sub> = 2.4 GHz	-	1	-	pF
N <sub>main</sub>	Main divider ratio		512	-	65535	
f <sub>PCmax</sub>	Maximum loop comparison frequency	indicative, not tested	-	-	4	MHz
AUX refere	nce divider input; pin 12					
f <sub>AUXin</sub>	Input frequency range		20	-	550	MHz
V <sub>AUXin</sub>	AC-coupled input signal level	$R_{in}$ (external) = $R_S = 50\Omega$ ; max. limit is indicative	-18	-	0	dBm
			80	-	632	mV <sub>PP</sub>
Z <sub>AUXin</sub>	Input impedance (real part)	$f_{VCO} = 500 \text{ MHz}$	-	3.9	-	kΩ
C <sub>AUXin</sub>	Typical pin input capacitance	f <sub>VCO</sub> = 500 MHz	-	0.5	-	pF
N <sub>AUX</sub>	Auxiliary division ratio		128	-	16383	
	divider input; pins 15, 16	1	-		1	1
f <sub>REFin</sub>	Input frequency range from TCXO		5	-	40	MHz
V <sub>RFin</sub>	AC-coupled input signal level	single-ended drive; max. limit is indicative	360	-	1300	mV <sub>PP</sub>
Z <sub>REFin</sub>	Input impedance (real part)	f <sub>REF</sub> = 20 MHz	-	10	-	kΩ
C <sub>REFin</sub>	Typical pin input capacitance	f <sub>REF</sub> = 20 MHz	-	1	-	pF
R <sub>REF</sub>	Reference division ratio	SA = SM = "000"	4	-	1023	
Charge pu	mp current setting resistor input; pin 14	•		- -		
R <sub>SET</sub>	External resistor from pin to ground		6	7.5	15	kΩ
V <sub>SET</sub>	Regulated voltage at pin	R <sub>SET</sub> = 7.5 kΩ	-	1.25	-	V
Charge pu	mp outputs (including fractional compensation	pump); pins 8, 9, 11; R <sub>SET</sub> = 7	.5 kΩ, FC =	80		-
I <sub>CP</sub>	Charge pump current ratio to I <sub>SET</sub> <sup>1</sup>	Current gain = I <sub>PH</sub> /I <sub>SET</sub>	-15		+15	%
IMATCH	Sink-to-source current matching	$V_{PH} = 1/2 V_{DDCP}$	-10		+10	%
IZOUT	Output current variation versus V <sub>PH</sub> <sup>2</sup>	V <sub>PH</sub> in compliance range	-10		+10	%
I <sub>LPH</sub>	Charge pump off leakage current	V <sub>PH</sub> = 1/2 V <sub>DDCP</sub>	-10		+10	nA
V <sub>PH</sub>	Charge pump voltage compliance		0.7	-	V <sub>DDCP</sub> -0.8	V

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### CHARACTERISTICS (continued)

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Phase nois	e (condition R <sub>SET</sub> = 7.5 kΩ, CP = 00)		•			
	Synthesizer's contribution to close-in phase noise of 900 MHz RF signal at 1 kHz offset.	GSM f <sub>REF</sub> = 13MHz, TCXO,	-	-90	-	dBc/Hz
0	Synthesizer's contribution to close-in phase noise of 1800 MHz RF signal at 1 kHz offset.	$f_{COMP} = 1MHz$ indicative, not tested	-	-83	-	dBc/Hz
£(f) -	Synthesizer's contribution to close-in phase noise of 800 MHz RF signal at 1 kHz offset.	TDMA f <sub>REE</sub> = 19.44MHz, TCXO,	-	-85	_	dBc/Hz
	Synthesizer's contribution to close-in phase noise of 2100 MHz RF signal at 1 kHz offset.	f <sub>COMP</sub> = 240kHz indicative, not tested	-	-77	_	dBc/Hz
Interface lo	ogic input signal levels; pins 2, 17, 18, 19, 20	·				
V <sub>IH</sub>	HIGH level input voltage		0.7*V <sub>DD</sub>	-	V <sub>DD</sub> +0.3	V
V <sub>IL</sub>	LOW level input voltage		-0.3	-	0.3*V <sub>DD</sub>	V
I <sub>LEAK</sub>	Input leakage current	logic 1 or logic 0	-0.5	-	+0.5	μA
Lock detec	t output signal (in push/pull mode); pin 1	·				
V <sub>OL</sub>	LOW level output voltage	I <sub>sink</sub> = 2mA	-	-	0.4	V
V <sub>OH</sub>	HIGH level output voltage	I <sub>source</sub> = -2mA	V <sub>DD</sub> -0.4	-	_	V

#### NOTES:

1.  $I_{SET} = \frac{V_{SET}}{R_{SET}}$  bias current for charge pumps.

2. The relative output current variation is defined as:

$$\frac{\Delta I_{OUT}}{I_{OUT}} = 2 \cdot \frac{(I_2 - I_1)}{I(I_2 + I_1)I}; \text{ with } V_1 = 0.7V, V_2 = V_{DDCP} - 0.8V \text{ (See Figure 3.)}$$

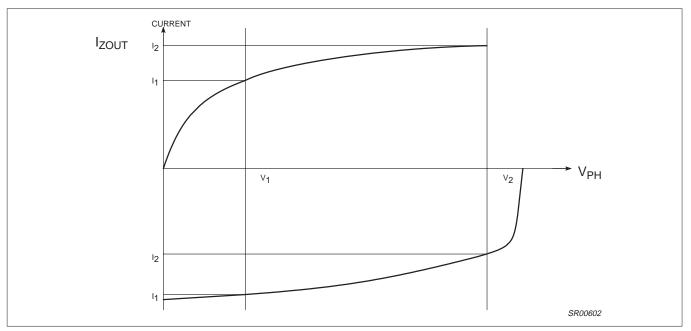


Figure 3. Relative Output Current Variation

#### FUNCTIONAL DESCRIPTION

#### Main Fractional-N divider

The RFin inputs drive a pre-amplifier to provide the clock to the first divider stage. For single ended operation, the signal should be fed to one of the inputs while the other one is AC grounded. The pre-amplifier has a high input impedance, dominated by pin and pad capacitance. The circuit operates with signal levels from –18 dBm to 0 dBm, and at frequencies as high as 2.5 GHz. The divider consists of a fully programmable bipolar prescaler followed by a CMOS counter. Total divide ratios range from 512 to 65536.

At the completion of a main divider cycle, a main divider output pulse is generated which will drive the main phase comparator. Also, the fractional accumulator is incremented by the value of NF. The accumulator works with modulo Q set by FMOD. When the accumulator overflows, the overall division ratio N will be increased by 1 to N + 1, the average division ratio over Q main divider cycles (either 5 or 8) will be

Nfrac = N + 
$$\frac{NF}{Q}$$

The output of the main divider will be modulated with a fractional phase ripple. The phase ripple is proportional to the contents of the fractional accumulator and is nulled by the fractional compensation charge pump.

The reloading of a new main divider ratio is synchronized to the state of the main divider to avoid introducing a phase disturbance.

#### Auxiliary divider

The AUXin input drives a pre-amplifier to provide the clock to the first divider stage. The pre-amplifier has a high input impedance, dominated by pin and pad capacitance. The circuit operates with signal levels from –18dBm to 0 dBm (80 to 636 mVpp), and at frequencies as high as 550 MHz. The divider consists of a fully programmable bipolar prescaler followed by a CMOS counter. Total divide ratios ranges from 128 to 16383.

#### **Reference divider**

The reference divider consists of a divider with programmable values between 4 and 1023 followed by a three bit binary counter. The 3 bit SM (SA) register (see figure 4) determines which of the 5 output pulses are selected as the main (auxiliary) phase detector input.

#### Phase detector (see Figure 5)

The reference and main (aux) divider outputs are connected to a phase/frequency detector that controls the charge pump. The pump current is set by an external resistor in conjunction with control bits CP0 and CP1 in the C-word (see Charge Pump table). The dead zone (caused by finite time taken to switch the current sources on or off) is cancelled by forcing the pumps ON for a minimum time at every cycle (backlash time) providing improved linearity.

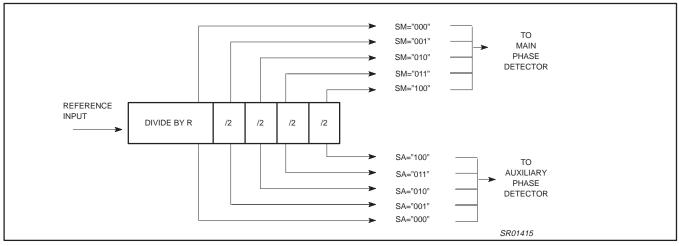


Figure 4. Reference Divider

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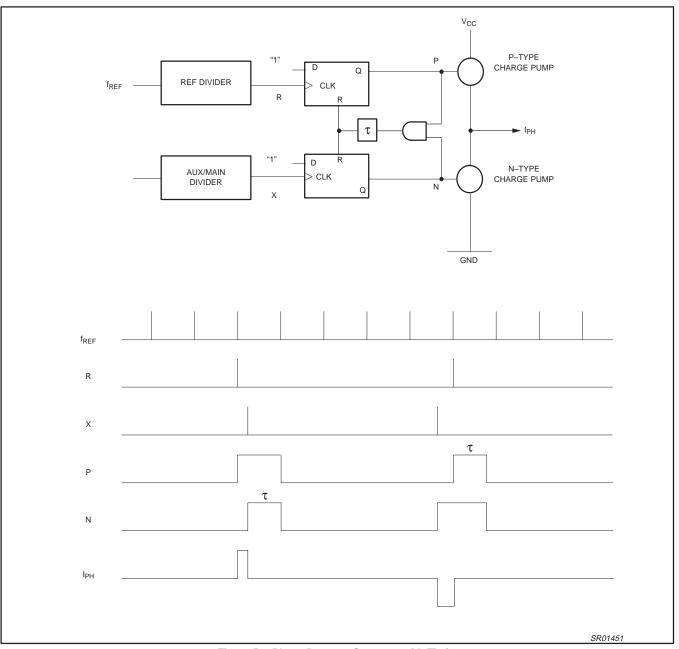


Figure 5. Phase Detector Structure with Timing

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The compensation is done by sourcing a small current,  $I_{COMP}$ , see

fractional compensation, the area of the fractional compensation

current pulse must be equal to the area of the fractional charge

to 128 VCO cycles, the amplitude is proportional to the fractional

accumulator value and is adjusted by FDAC values (bits FC7-0 in

main charge pump in that it follows all the current scaling through

For a given charge pump,

80 for FMOD = 0 (modulo 8).

FRD is the fractional accumulator value.

the B-word). The fractional compensation current is derived from the

external resistor setting, R<sub>SET</sub>, programming or speed-up operation.

The target values for FDAC are: 128 for FMOD = 1 (modulo 5) and

 $I_{COMP} = (I_{PUMP} / 128) * (FDAC / 5*128) * FRD$ 

Figure 7, that is proportional to the fractional error phase. For proper

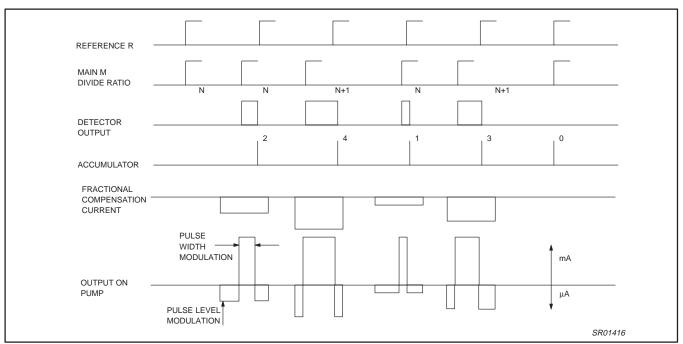
pump ripple. The width of the fractional compensation pulse is fixed

#### Main Output Charge Pumps and Fractional **Compensation Currents (see Figure 6)**

The main charge pumps on pins PHP and PHI are driven by the main phase detector and the charge pump current values are determined by the current at pin R<sub>SET</sub> in conjunction with bits CP0, CP1 in the C-word (see table of charge pump ratios). The fractional compensation is derived from the current at R<sub>SET</sub>, the contents of the fractional accumulator FRD and by the program value of the FDAC. The timing for the fractional compensation is derived from the main divider. The main charge pumps will enter speed up mode after the A-word is set and strobe goes High. When strobe goes Low, charge pump will exit speed up mode.

#### Principle of Fractional Compensation

The fractional compensation is designed into the circuit as a means of reducing or eliminating fractional spurs that are caused by the fractional phase ripple of the main divider. If I<sub>COMP</sub> is the compensation current and  $\mathsf{I}_{\mathsf{PUMP}}$  is the pump current, then for each charge pump:



#### IPUMP TOTAL = IPUMP + ICOMP.

NOTE: For a proper fractional compensation, the area of the fractional compensation current pulse must be equal to the area of the charge pump ripple output. Figure 6. Waveforms for NF = 2 Modulo 5  $\rightarrow$  fraction =  $^{2}/_{5}$ 

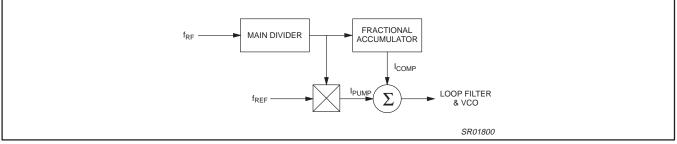


Figure 7. Current Injection Concept

#### **Auxiliary Output Charge Pumps**

The auxiliary charge pump on pin PHA are driven by the auxiliary phase detector and PHP, PHI are driven by the main phase detector. The current value is determined by the external resistor attached to pin R<sub>SET</sub>.

#### Main and auxiliary charge pump currents

CP1	CP0	I <sub>PHA</sub>	I <sub>PHP</sub>	I <sub>PHP-SU</sub>	I <sub>PHI</sub>
0	0	1.5xl <sub>SET</sub>	3xI <sub>SET</sub>	15xl <sub>SET</sub>	36xI <sub>SET</sub>
0	1	0.5xl <sub>SET</sub>	1xl <sub>SET</sub>	5xl <sub>SET</sub>	12xl <sub>SET</sub>
1	0	1.5xl <sub>SET</sub>	3xI <sub>SET</sub>	15xl <sub>SET</sub>	0
1	1	0.5xl <sub>SET</sub>	1xl <sub>SET</sub>	5xl <sub>SET</sub>	0

#### NOTES

1.  $I_{SET} = V_{SET}/R_{SET}$  bias current for charge pumps.

2. CP1 is used to disable the PHI pump, IPHP-SU is the total current at pin PHP during speed up condition.

#### Lock Detect

The output LOCK maintains a logic '1' when the auxiliary phase detector ANDed with the main phase detector indicates a lock condition. The lock condition for the main and auxiliary synthesizers is defined as a phase difference of less than  $\pm 1$  period of the frequency at the input REF<sub>in+, -</sub>. One counter can fulfill the lock condition when the other counter is powered down. Out of lock (logic '0') is indicated when both counters are powered down.

#### Power-down mode

The power-down signal can be either hardware (PON) or software (PD). The PON signal is exclusively ORed with the PD bits in B-word. If PON = 0, then the part is powered up when PD = 1. PON can be used to invert the polarity of the software bit PD. When the synthesizer is reactivated after power-down, the main and reference dividers are synchronized to avoid possibility of random phase errors on power-up.

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data is latched into different working registers or temporary

DAC are not loaded immediately. Instead they are stored in

temporary registers. Only when the A-word is loaded, these

registers. In order to fully program the synthesizer, 3 words must be

each word. The D word is normally used for testing purposes. When

sending the B-word, data bits FC7-0 for the fractional compensation

temporary registers are loaded together with the main divider ratio.

sent: C, B, and A. Table 1 shows the format and the contents of

#### Serial programming bus

The serial input is a 3-wire input (CLOCK, STROBE, DATA) to program all counter divide ratios, fractional compensation DAC, selection and enable bits. The programming data is structured into 24 bit words; each word includes 2 or 3 address bits. Figure 8 shows the timing diagram of the serial input. When the STROBE goes active HIGH, the clock is disabled and the data in the shift register remains unchanged. Depending on the address bits, the

#### Serial bus timing characteristics. See Figure 8.

 $V_{DD} = V_{DDCP} = +3.0V$ ;  $T_{amb} = +25^{\circ}C$  unless otherwise specified.

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT	
Serial program	ming clock; CLK	·	•			
t <sub>r</sub>	Input rise time	-	10	40	ns	
t <sub>f</sub>	Input fall time	-	10	40	ns	
T <sub>cy</sub>	Clock period	100	-	-	ns	
Enable program	nming; STROBE		•			
t <sub>START</sub>	Delay to rising clock edge	40	-	-	ns	
t <sub>W</sub>	Minimum inactive pulse width	1/f <sub>COMP</sub>	-	-	ns	
t <sub>SU;E</sub>	Enable set-up time to next clock edge	20	-	-	ns	
Register serial	input data; DATA	·		•		
t <sub>SU;DAT</sub>	Input data to clock set-up time	20	-	_	ns	
t <sub>HD;DAT</sub>	Input data to clock hold time	20	-	-	ns	

#### Application information

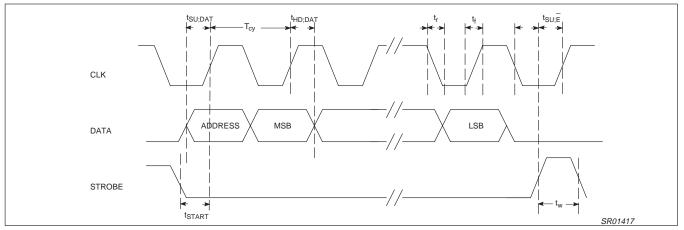


Figure 8. Serial Bus Timing Diagram

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#### Data format

#### Table 1. Format of programmed data

Last In		MSB		Serial Programming Format					
p23	p22	p21	p20	/	/	р1	p0		

#### Table 2. A word, length 24 bits

Last	In					MSB															LSB	First In		
Addre	ess	fmod	Frac	tional	-N	Main D	ivider	ratio														Spare		
0	0	FM	NF2	NF1	NF0	N15	N14	N13	N12	N11	N10	N9	N8	N7	N6	N5	N4	N3	N2	N1	N0	SK1	SK2	
Defa	ault	0	0	1	0	0	0	1	0	0	0	1	0	0	0	1	1	0	0	0	0	0	0	
A wo	rd sele	ect			Fixed	to 00.																		
Fract	ional I	Modulus	s sele	ct	FM 0	= modu	lo 8, 1	l = mo	odulo	5.														
Fract	ional-l	N Increi	ment		NF2	0 Fracti	onal N	Incre	ement	value	es 000	to 11	1.											
N-Div	N-Divider N0N15, Main divider values 512 to 65535 allowed for divider ratio.																							

#### Table 3. B word, length 24 bits

Address			Reference Divider									Lock PD		Fractional Compensation DAC									
0	1	R9	R8	R7	R6	R5	R4	R3	R2	R1	R0	L1	L0	Main	Aux	FC7	FC6	FC5	FC4	FC3	FC2	FC1	FC0
Defa	ault	0	0	0	1	0	1	0	0	0	1	0	0	1	1	0	1	0	1	0	0	0	0
B word select					Fixed to 01																		
R-Divider				R0R9, Reference divider values 4 to 1023 allowed for divider ration.																			
Lock d	etect o		01 10 11	Com Com Main Auxil	bined lock iary lo	main detec oop lo	, aux t sign ck de	, lock al pre etect s	deteo esent signal	ct sigr at the prese	hal pro LOC ent at	esent at esent at K pin (p the LO0 down n	the LC bush/pu CK pin	CK pi II). (push/	n (öpe ′pull).	n draí	n).						
Power down				Main = 1: power to N-divider, reference divider, main charge pumps, $Main = 0$ to power down. Aux = 1: power to Aux divider, reference divider, aux charge pump, $Aux = 0$ to power down.																			
Fractional Compensation					FC70 Fractional Compensation charge pump current DAC, values 0 to 255.																		

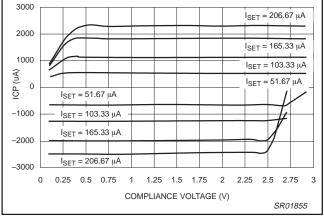
#### Table 4. C word, length 24 bits

Addı	ress				Auxiliary Divider									СР		SM		SA					
1	0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0	CP1	CP0	SM2	SM1	SM0	SA2	SA1	SA0
Defa	ault	0	0	0	0	0	1	1	1	0	0	1	0	1	0	1	1	0	0	0	0	0	0
C word select				Fixed to 10																			
A-Divi	der				A0A13, Auxiliary divider values 128 to 16383 allowed for divider ratio.																		
Charg	Charge pump current Ratio					CP1, CP0: Charge pump current ratio, see table of charge pump currents.																	
Main comparison select					SM comparison divider select for main phase detector.																		
Aux co	ompari	son se	elect		SA Comparison divider select for auxiliary phase detector.																		

#### Table 5. D word, length 24 bits

A	ddres	s	Sy	nthes	sizer T	est Bi	its							Sy	nthes	izer T	est Bi	its					
1	1	0	-	-	-	-	-	Tspu	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	Defaul	t	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
Tspu	u: Spee	ed up :	= 1					main o test bit								ne.							

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#### TYPICAL PERFORMANCE CHARACTERISTICS



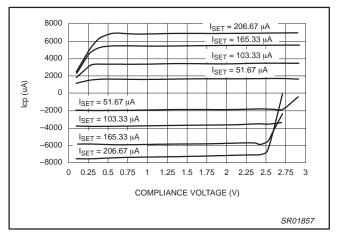


Figure 11. PHI Charge Pump vs.  $I_{SET}$ (CP = 00; TEMP = 25°C)

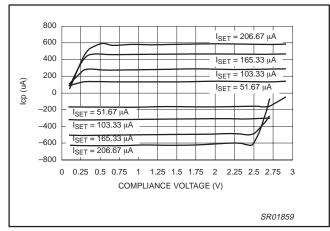


Figure 13. PHP Charge Pump Output vs.  $I_{SET}$ (CP = 10; Temp = 25°C)

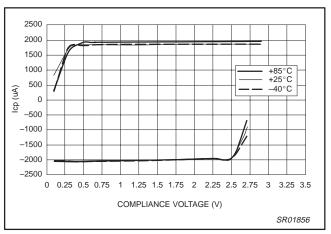


Figure 10. PHI Charge Pump Output vs. Temperature (CP = 01;  $V_{DD}$  = 3.0 V;  $I_{SET}$  = 165.33  $\mu$ A)

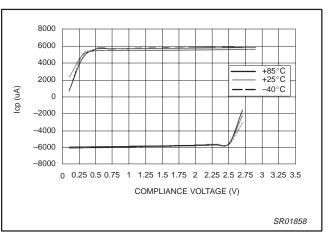


Figure 12. PHI Charge Pump Output vs. Temperature (CP = 00; V<sub>DD</sub> = 3.0 V; I<sub>SET</sub> = 165.33  $\mu$ A)

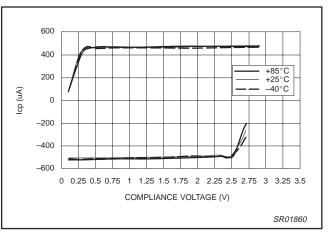
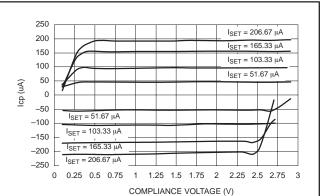


Figure 14. PHP Charge Pump Output vs. Temperature (CP = 10; V<sub>DD</sub> = 3.0 V; I<sub>SET</sub> = 165.33  $\mu$ A)

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#### TYPICAL PERFORMANCE CHARACTERISTICS (Continued)



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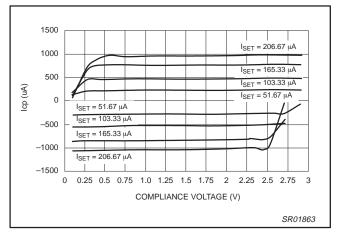


Figure 17. PHP–SU Charge Pump Output vs.  $I_{SET}$ (CP = 01; Temp = 25°C)

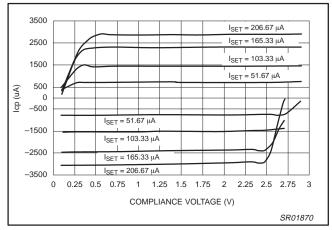


Figure 19. PHP–SU Charge Pump Output vs.  $I_{SET}$ (CP = 00; Temp = 25°C)

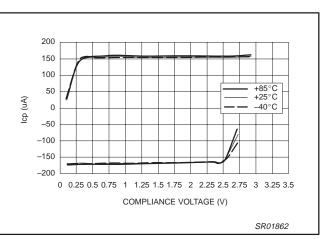


Figure 16. PHP Charge Pump Output vs. Temperature (CP = 11;  $V_{DD}$  = 3.0 V;  $I_{SET}$  = 165.33  $\mu$ A)

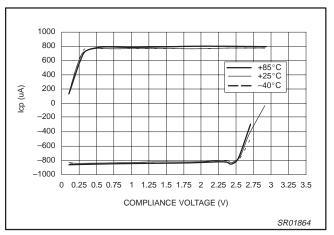


Figure 18. PHP–SU Charge Pump Output vs. Temperature (CP = 01; V<sub>DD</sub> = 3.0 V; I<sub>SET</sub> = 165.33  $\mu$ A)

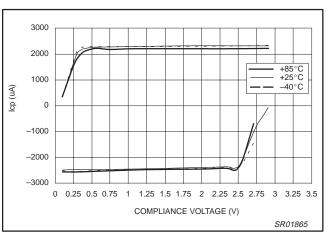
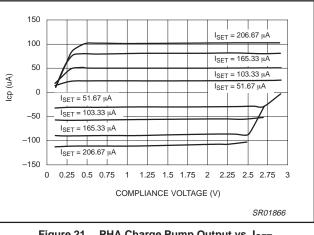


Figure 20. PHP–SU Charge Pump Output vs. Temperature (CP = 00; V<sub>DD</sub> = 3.0 V; I<sub>SET</sub> = 165.33  $\mu$ A)

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#### TYPICAL PERFORMANCE CHARACTERISTICS (Continued)



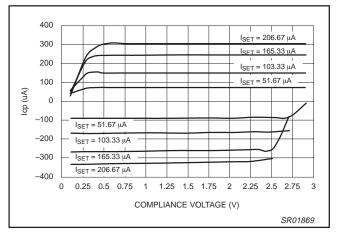
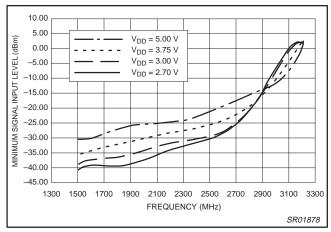
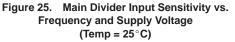


Figure 23. PHA Charge Pump Output vs.  $I_{SET}$ (CP = 10; Temp = 25°C)





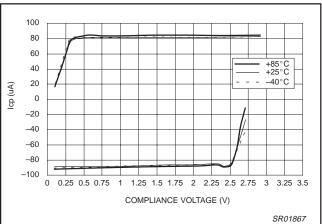


Figure 22. PHA Charge Pump Output vs. Temperature (CP = 11; V<sub>DD</sub> = 3.0 V; I<sub>SET</sub> = 165.33  $\mu$ A)

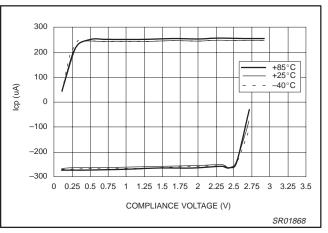


Figure 24. PHA Charge Pump Output vs. Temperature (CP = 10;  $V_{DD}$  = 3.0 V; I<sub>SET</sub> = 165.33  $\mu$ A)

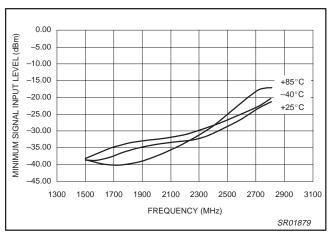
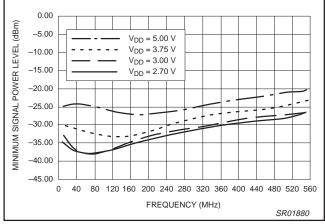
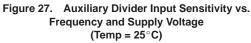


Figure 26. Main Divider Input Sensitivity vs. Frequency and Temperature (V<sub>DD</sub> = 3.00 V)

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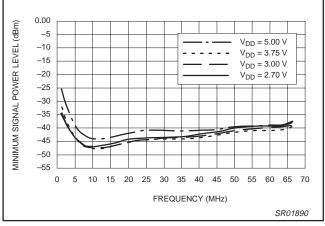


Figure 29. Reference Divider Input Sensitivity vs. Frequency and Supply Voltage (Temp = 25°C)

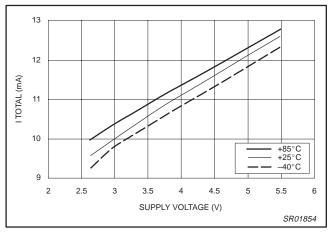
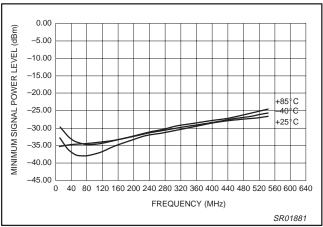
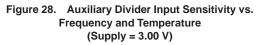


Figure 31. Current Supply Over  $V_{DD}$ 





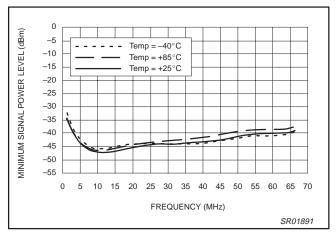
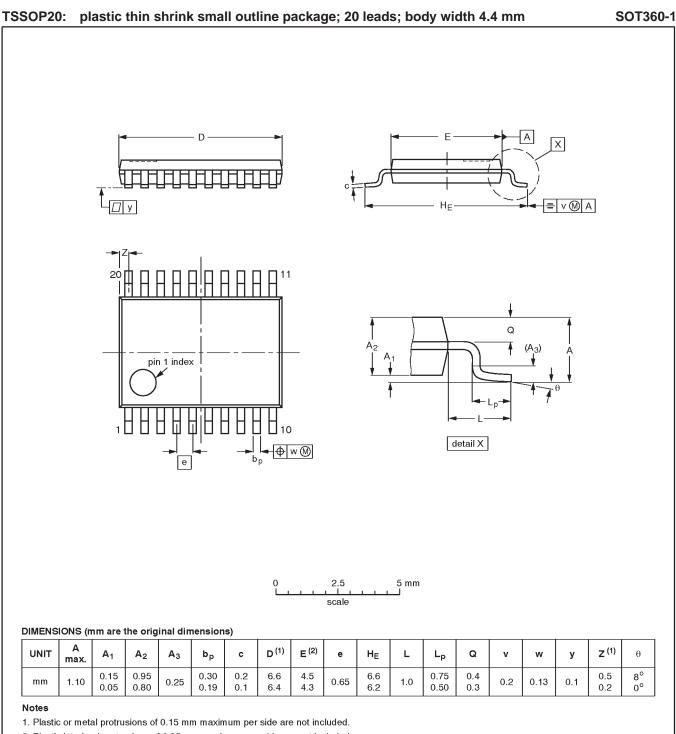


Figure 30. Reference Divider Input Sensitivity vs. Frequency and Temperature (V<sub>DD</sub> = 3.00 V)

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Product specification



2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ	PROJECTION	1550E DATE
SOT360-1		MO-153AC			<del>-93-06-16-</del> 95-02-04

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#### Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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